	Type	L #	Hits	Search Text	DBs	Time Stamp
1	BRS	L1	1466	database and inspect$3 and (shape or size)and(wafer$1 or semconductor$1 or subtrate$1 or chip$1 or printed adj circuit adj board or PCB)	USPAT; EPO; JPO; USOCR	2003/04/11 11:58
2	BRS	L2	0	1 and inspect$3 near6 generator adj3 coupl$2	USPAT; EPO; JPO; USOCR	2003/04/11 12:00
3	BRS	L3	7	1 and inspect$3 near6 generator	USPAT; EPO; JPO; USOCR	2003/04/11 12:00
4	BRS	L4	0	3 and inspect$3 near6 plan	USPAT; EPO; JPO; USOCR	2003/04/11 12:15
5	BRS	L5	1384	1 and (camera or CCD or sens$4 or detect$4 or scann$3)	USPAT; EPO; JPO; USOCR	2003/04/11 12:07
6	BRS	L6	1384	1 and 5	USPAT; EPO; JPO; USOCR	2003/04/11 12:07
7	BRS	L7	76	6 and image near6 model	USPAT; EPO; JPO; USOCR	2003/04/11 12:08
8	BRS	L8	0	7 and structural near6 model	USPAT; EPO; JPO; USOCR	2003/04/11 12:09
9	BRS	L9	2	7 and geometric near5 model	USPAT; EPO; JPO; USOCR	2003/04/11 12:10

	Type	L #	Hits	Search Text	DBs	Time Stamp
10	BRS	L10	2	1 and 5 and 6 and 7 and 9	USPAT; EPO; JPO; USOCR	2003/04/11 12:11
11	BRS	L11	14	7 and inspect$3 near6 model	USPAT; EPO; JPO; USOCR	2003/04/11 12:16

	Document ID	Kind Codes	Source	Issue Date	Pages
1	US 6483938 B1		USPAT	20021119	53
2	US 6324298 B1		USPAT	20011127	33
3	US 6317513 B1		USPAT	20011113	19
4	US 6292582 B1		USPAT	20010918	53
5	US 6246787 B1		USPAT	20010612	52
6	US 6205239 B1		USPAT	20010320	53
7	US 6091846 A		USPAT	20000718	56
8	US 6023328 A		USPAT	20000208	7
9	US 5982927 A		USPAT	19991109	20
10	US 5912984 A		USPAT	19990615	16
11	US 5615367 A		USPAT	19970325	42
12	US 5307421 A		USPAT	19940426	13
13	US 4852131 A		USPAT	19890725	16

	Title
1	System and method for classifying an anomaly
2	Automated wafer defect inspection system and a process of performing such inspection
3	Method and apparatus for inspecting solder paste using geometric constraints
4	Method and system for identifying defects in a semiconductor
5	System and method for knowledgebase generation and management
6	System and method for circuit repair
7	Method and system for anomaly detection
8	Photomask inspection method and apparatus
9	Methods and apparatuses for in-line solder paste inspection
10	Method and apparatus for in-line solder paste inspection
11	System and methods including automatic linking of tables for improved relational database modeling with interface
12	Process for producing a synthesized reference image for the inspection of objects and apparatus for performing the same
13	Computed tomography inspection of electronic devices

	Abstract	Current OR
1		382/149
2		382/149
3		382/145
4		382/149
5		382/141
6		382/149
7		382/145
8		356/237.4
9		382/168
10		382/149
11		707/102
12		382/145
13		378/4

	Retrieval Classif	Current XRef	Inventor	U	S	C	P	1	2	3	4
1		382/218; 382/224	Hennessey, A. Kathleen et al.	☐	☒	☐	☐	☐	☐	☐	☐
2		257/E21.53	O'Dell, Jeffrey et al.	☐	☒	☐	☐	☐	☐	☐	☐
3		382/147	Michael, David J. et al.	☒	☐	☐	☐	☐	☐	☐	☐
4		348/126; 382/145; 382/155; 382/159	Lin, YouLing et al.	☒	☐	☐	☐	☐	☐	☐	☐
5		250/559.45; 356/237.1	Hennessey, A. Kathleen et al.	☒	☐	☐	☐	☐	☐	☐	☐
6		382/151; 382/209	Lin, YouLing et al.	☒	☐	☐	☐	☐	☐	☐	☐
7		257/E21.525; 257/E21.53; 382/149; 382/151; 382/168	Lin, YouLing et al.	☒	☐	☐	☐	☐	☐	☐	☐
8		356/237.5	Pierrat, Christophe	☒	☐	☐	☐	☐	☐	☐	☐
9		382/145	Koljonen, Juha	☒	☐	☐	☐	☐	☐	☐	☐
10		382/181	Michael, David J. et al.	☒	☐	☐	☐	☐	☐	☐	☐
11		345/700	Bennett, John G. et al.	☒	☐	☐	☐	☐	☐	☐	☐
12		345/418; 382/155; 382/218	Darboux, Michel et al.	☒	☐	☐	☐	☐	☐	☐	☐
13		378/17; 378/58; 382/147; 382/150	Armistead, Robert A.	☒	☐	☐	☐	☐	☐	☐	☐

	5	Image Doc. Displayed	PT
1	☐	US 6483938	☐
2	☐	US 6324298	☐
3	☐	US 6317513	☐
4	☐	US 6292582	☐
5	☐	US 6246787	☐
6	☐	US 6205239	☐
7	☐	US 6091846	☐
8	☐	US 6023328	☐
9	☐	US 5982927	☐
10	☐	US 5912984	☐
11	☐	US 5615367	☐
12	☐	US 5307421	☐
13	☐	US 4852131	☐

	Document ID	Kind Codes	Source	Issue Date	Pages
14	US 4616121 A		USPAT	19861007	17

	Title
14	Automatic welding with imaging of workpiece surfaces and of the junction between the surfaces

	Abstract	Current OR
14		219/124.34

	Retrieval Classif	Current XRef	Inventor	U	S	C	P	1	2	3	4
14		318/577; 901/42; 901/47	Clocksin, William F. et al.	☒	☐	☐	☐	☐	☐	☐	☐

	5	Image Doc. Displayed	PT
14	☐	US 4616121	☐